

Enhancement Mode P-Channel Power MOSFET

 $TO-252/PMOS/-20V/\pm12V/-0.8V/-60A/5.6m\Omega$

Rev1.0





Enhancement Mode P-Channel Power MOSFET

1.Features

- ◆ Fast Switching
- ◆ Improved dv/dt Capability
- ♦ 100% RG Tested
- ♦ 100% UIS Tested

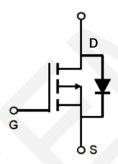
- Load Switch
- PWM Application
- Power management



Pin Description

TO252





Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WP2060P	WP2060P	TO-252	2,500	25,000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Value	Units
Drain to Source Voltage	V _{DS}	-20	V
Gate to Source Voltage	V_{GS}	±12	V
Drain Current (DC)	I _D -60		А
Drain Current (Pulse), PW≤300μs	I _{DP}	-240	А
Total Dissipation	P _D	70	W
Avalanche Energy, Single Pulsed	Eas	110	mJ
Junction Temperature	Tj	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Junction to ambient	ReJA	2.1	°C/W

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

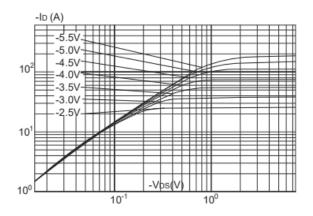
6.Electrical Characteristics at Ta=25°C (Note 3)

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = -250 \mu A$, $V_{GS} = 0 V$	-20	-	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	$V_{DS} = -20V$, $V_{GS} = 0V$	-	1	-1	μΑ
Gate to Source Leakage Current	Igss	V _{GS} = ±12V	ı	1	±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _{DS} =-250µA	-0.5	-0.8	-1.1	V
Static Drain to Source On-State	R _{DS(on)}	I _D = -10A, V _{GS} = -4.5V	1	5.6	7.0	mΩ
Resistance		I _D =-5A, V _{GS} = -2.5V	-	7.8	11	mΩ
Input Capacitance	Ciss	V _{GS} =0V,	-	4590	-	pF
Output Capacitance	Coss	V _{DS} =-10V,	-	505	-	pF
Reverse Transfer Capacitance	Crss	Frequency=1.0MHz	-	440	-	pF
Turn-ON Delay Time	t _{d(on)}	I _D = -14A,	-	8	-	ns
Rise Time	tr	V _{DS} =-10V,	-	59	-	ns
Turn-OFF Delay Time	$t_{\sf d(off)}$	R _{GEN} = 2.7Ω ,	-	111	-	ns
Fall Time	tf	V _{GS} =-10V,	-	43	-	ns
	Qg	V _{DS} =-10 V, V _{GS} =-4.5V, I _D = -15A	-	46	-	nC
Total Gate Charge	Qgs		-	7.3	-	nC
	Q _{gd}		-	10	-	nC
Diode Forward Voltage	V _{FSD}	I _{SD} = -10A,V _{GS} =0V	-0.5	-0.8	-1.1	V

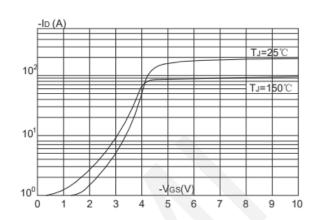
Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



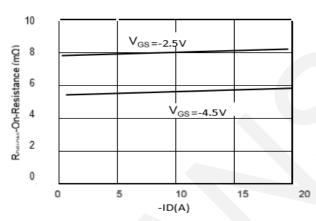
7. Typical electrical and thermal characteristics



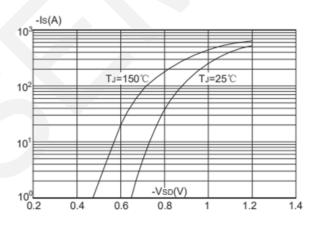




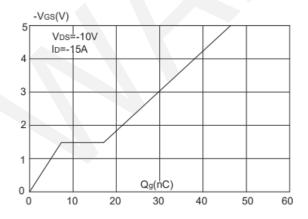
Typical Transfer Characteristics



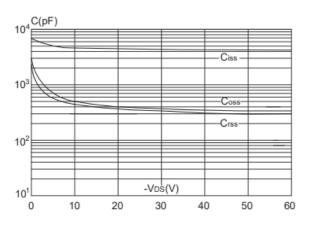
On-Resistance vs. Drain Current and Gate



Body Diode Characteristics

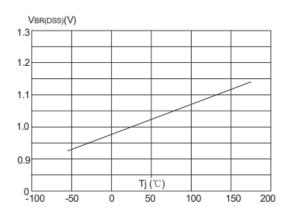


Gate Charge Characteristics

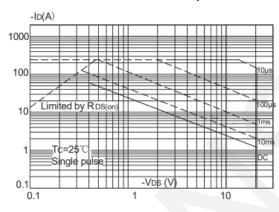


Capacitance Characteristics

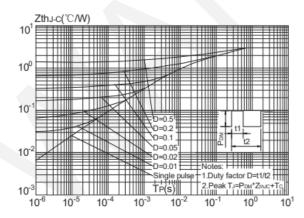




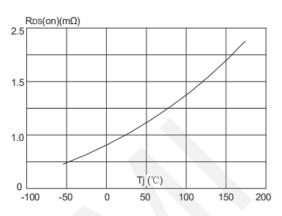
Normalized Breakdown Voltage vs. Junction Temperature



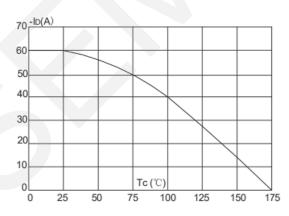
Maximum Safe Operating Area



Maximum Effective Transient Thermal Impedance, Junction-to Case



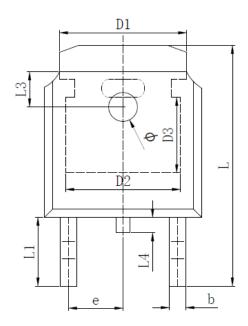
Normalized on Resistance vs. Junction Temperature

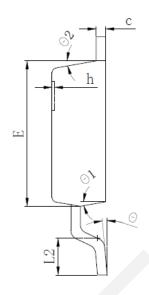


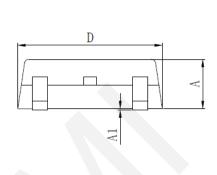
Maximum Continuous Drain Current vs. Case Temperature



8.Package Dimensions







SYMBOL	MILLIMETER			
	MIN	Тур.	MAX	
A	2. 200	2. 300	2. 400	
A1	0.000		0. 127	
b	0.640	0.690	0.740	
c(电镀后)	0. 460	0. 520	0. 580	
D	6. 500	6. 600	6. 700	
D1	5. 334 REF			
D2	4.826 REF			
D3	3.166 REF			
E	6. 000	6. 100	6. 200	
e	2.286 TYP			
h	0.000	0.100	0. 200	
L	9. 900	10. 100	10.300	
L1	2.888 REF			
L2	1. 400	1.550	1.700	
L3	1.600 REF			
L4	0.600	0.800	1.000	
ф	1. 100	1. 200	1. 300	
θ	0°		8°	
θ 1	9° TYP			
θ2	9° TYP			



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